

N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY		
V _{DS}	80	V
$R_{DS(on)} V_{GS} = 10 V$	7	mΩ
$R_{DS(on)}$ $V_{GS} = 4.5 \text{ V}$	9	mΩ
I _D	100	Α
Configuration	Single	

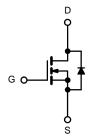
FEATURES

- TrenchFET® Power MOSFET
- \bullet 100 % R_g and UIS Tested

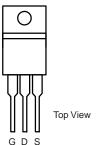


APPLICATIONS

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting



N-Channel MOSFET



ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless	otherwise note	d)	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	80	V	
Gate-Source Voltage	V _{GS}	± 20	v	
	T _C = 25 °C		100ª	
Ocation and Ducin Occurrent (T. 150 °O)	T _C = 70 °C	_	85 ^a	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	28.6 ^{b, c}	
	T _A = 70 °C		24.9 ^{b, c}	1
Pulsed Drain Current (t = 100 μs)	I _{DM}	350	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	,	80 ^a	
	T _A = 25 °C	I _S	4.5 ^{b, c}	
Single Pulse Avalanche Current	. 0.1!!	I _{AS}	30	
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	45	mJ
Maximum Power Dissipation	T _C = 25 °C		180	
	T _C = 70 °C		120	14/
	T _A = 25 °C	P _D	5b, c	W
	T _A = 70 °C		3.2 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	00
Soldering Recommendations (Peak Temperatur	Ţ.	260	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Manifesture has ation to Archiveta	t ≤ 10 sec	R _{thJA}	15	18	°C/W	
Maximum Junction-to-Ambient ^a	Steady State		40	50		
Maximum Junction-to-Case		R _{thJC}	0.85	1.1		

Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.



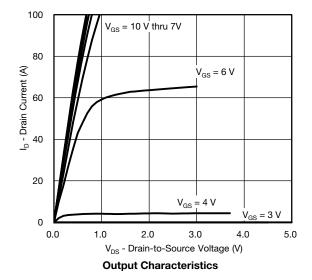
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	<u> </u>				l .	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	80			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			37		1400
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu A$		- 6.1		mV/°C
Gate-Source Threshold Voltage	V _{GS(th})	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		3.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
	_	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80 V, V _{GS} = 0 V, T _J = 55 °C			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	85			Α
	=(=:,/	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		7		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 6 V, I _D = 15 A		7. 5		mΩ
	==(=:.)	V _{GS} = 4.5 V, I _D = 10 A		9		
Forward Transconductance ^a	g _{fs}	$V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		60		S
Dynamic ^b						
Input Capacitance	C _{iss}			3855		
Output Capacitance	C _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1120		pF
Reverse Transfer Capacitance	C _{rss}			376		1
Total Gate Charge	Qg	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5		
		$V_{DS} = 40 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 10 \text{ A}$		22	22	
				18		1 _
Gate-Source Charge	Q _{gs}	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3		nC
Gate-Drain Charge	Q_{qd}			7.3		-
Output Charge	Q _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86	1
Gate Resistance	R_g	f = 1 MHz	0.5	1.3	2	Ω
Turn-On Delay Time	t _{d(on)}			12	24	
Rise Time	t _r	$V_{DD} = 40 \text{ V}, R_{L} = 4 \Omega$		8	16	1
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		32	64	1
Fall Time	t _f			7	14	1
Turn-On Delay Time	t _{d(on)}			14	28	ns
Rise Time	t _r	$V_{DD} = 40 \text{ V}, R_1 = 4 \Omega$		11	22	-
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_g = 1 \Omega$		30	60	
Fall Time	t _f			8	16	
Drain-Source Body Diode Characteristic	s				I.	•
Continuous Source-Drain Diode Current	Is	T _C = 25 °C			75	
Pulse Diode Forward Current (t = 100 μs)	I _{SM}				150	A
Body Diode Voltage	V_{SD}	I _S = 5 A		0.76	1.1	V
Body Diode Reverse Recovery Time	t _{rr}			38	75	ns
Body Diode Reverse Recovery Charge	Q_{rr}	1 10 A 11/44 100 A/ - T 05 20		36	70	nC
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		19		
Reverse Recovery Rise Time	t _b			19		ns

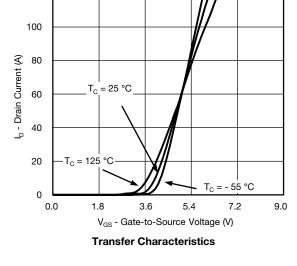
Notes

- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

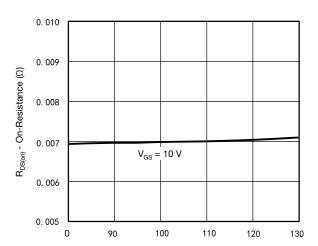
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

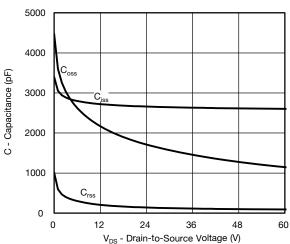


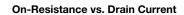


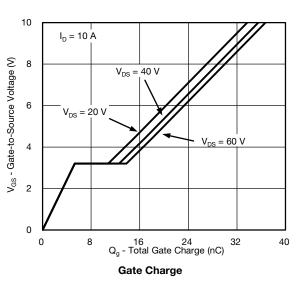


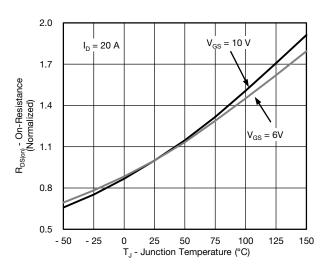
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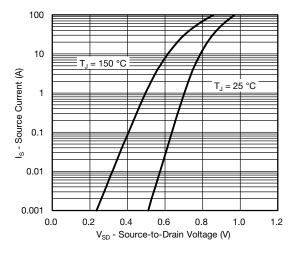




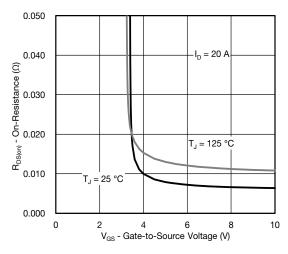
Capacitance

On-Resistance vs. Junction Temperature

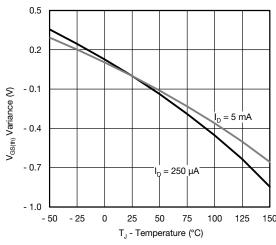




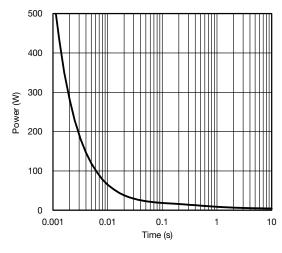
Source-Drain Diode Forward Voltage



On-Resistance vs. Gate-to-Source Voltage

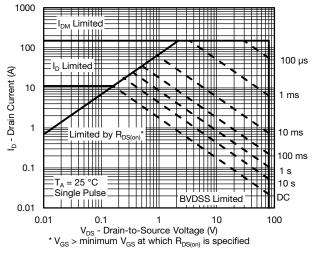


Threshold Voltage



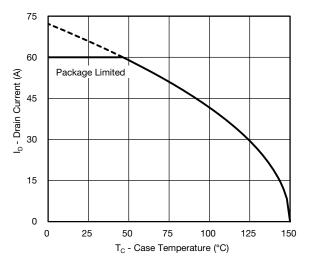
Single Pulse Power, Junction-to-Ambient

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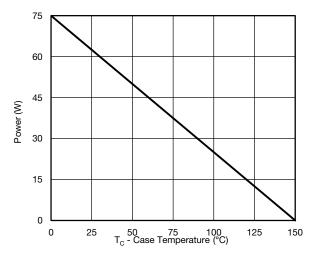


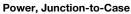
Safe Operating Area, Junction-to-Ambient

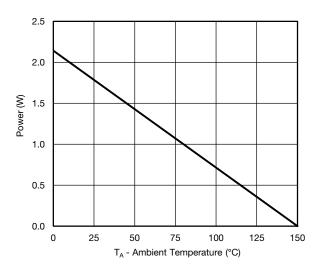




Current Derating*



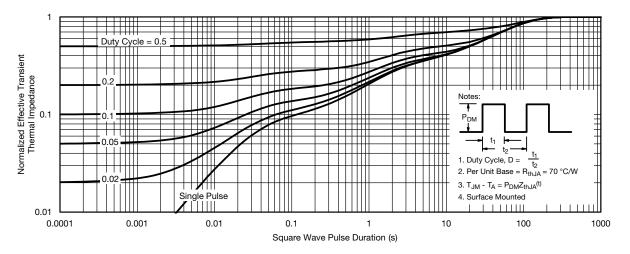




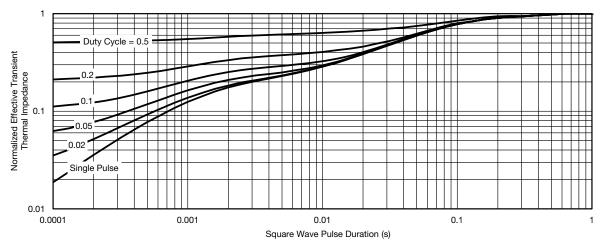
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





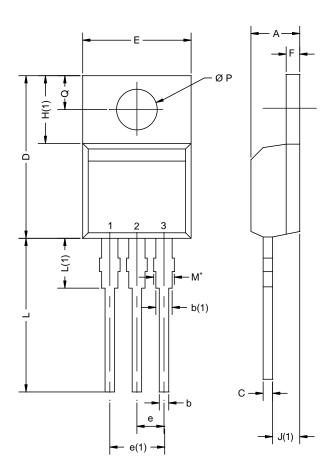
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12					

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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